




<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10668010</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>SINHA ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
307	651	10/11/2006	HK
374	172	10/11/2006	HK
374	176	10/11/2006	HK
702	99	10/11/2006	HK
365	211	10/11/2006	HK

U.S. Patent and Trademark Office	Part of Paper No.: 20061011
----------------------------------	-----------------------------

<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10668010	SINHA ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
374/1,170,172,176,178 (consulted Gail Verbitsky)	02/14/2006	HK
702/99,130 (consulted Bryan Bui)	02/15/2006	HK
365/211,222 (consulted Amir Zarabian)	10/11/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/11/2006	HK
U.S. Patent and Trademark Office		Part of Paper No.: 20061011

<b>Interference Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10668010	SINHA ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
Interference Search History		10/11/2006	HK
Printout			

---

U.S. Patent and Trademark Office	Part of Paper No.:	20061011
----------------------------------	--------------------	----------